2021 IEEE 22nd Latin American Test Symposium (LATS 2021)

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TECHNICAL PROGRAM

Opening Session (Message from the Organizing Committee)

General Chairs:
Raoul Velazco – TIMA (France)
Yervant Zorian – Synopsys (USA)

Program Chairs:
Letícia Maria Bolzani Pöhls – RWTH Aachen University (Germany)
Fabian Luis Vargas – PUCRS (Brazil)

Invited Talk 1

Session Chairs: Yervant Zorian, Synopsys (USA) and Fabian Luis Vargas, PUCRS (Brazil)

Hardware Security and Machine Learning: Hero or Hoax?...N/A
Prof. Giorgio di Natale, Université Grenoble Alpes (France)

Session 1: Diagnosis and On-Line Monitoring of Analog Circuits

Session Chair: Tiago Balen, UFRGS (Brazil)

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Prof. Krishnendu Chakrabarty, Duke University (USA)

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Session Chair: Raoul Velazco, TIMA Lab (France)

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Invited Talk 2

Session Chair: Raoul Velazco, TIMA Lab (France)

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Session Chair: Jarbas Silveira, UFC (Brazil)

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Session Chair: Felipe Restrepo Calle, Universidad Nacional de Colombia (Colombia)

Invited Talk 4

Session Chair: Fabian Luis Vargas, PUCRS (Brazil)

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Session Chair: Ievgen Kabin, IHP GmbH (Germany)

Industry Talk 2

Session Chair: Hans-Joachim Wunderlich, University of Stuttgart (Germany)

Soft Error becomes a Hard Problem for the Future Electronic Devices...N/A
Dr. Sung S. Chung, CTO, QRT Inc. Korea (Korea)

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Session Chair: Julio Perez Acle, Universidad de la Republica de Uruguay (Uruguay)

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